

PCN 12_0117 Wafer Fab Transfer and Halogen Free Material Change

Qualification Data for AD5100

QUALIFICATION RESULTS AD5100			
TEST	CONDITIONS	SAMPLE SIZE (LOT/QTY)	RESULTS
Autoclave ^{1,2}	JESD22-A102, 121°C 100%RH, 96hrs	3 x 77	Pass
Biased HAST ^{1,3}	JESD22-A110, 130°C, 85% RH, 96hrs	3 x 77	Pass
High Temperature Storage Life ¹	JESD22-A103, 150°C, 1000hrs	1 x 73	Pass
Temperature Cycling ^{1,3}	JESD22-A104, 65°C/+150°C, 500 Cycles	3 x 77	Pass
Solder Heat Resistance ^{1,2}	ADI-0049 – MSL1	3 x 16	Pass
Early Life Failure (ELF) ²	MIL-STD-883, Method 1015	3 x 800	Pass
High Temperature Operating Life (HTOL) ⁴	JESD22-A108, 125°C<T _j <135°C, Biased, 1,000 Hours	3 x 77	Pass
ESD – FICDM ³	JESD22-C101, 1Ω, Cpkg	Pass 1500V	
ESD – HBM ³	ANSI/ESDA/JEDEC JS-001-2010 1.5kΩ, 100pF	Pass 3500V	
ESD – MM ³	ANSI/ESD STM5.2, 0Ω, 200pF	Pass 200V	
Latch-up ³	JESD-78	Pass 100mA	

¹ Preconditioned per JEDEC/IPC J-STD-020 MSL 1

² Electrical test was performed at room temperature.

³ Pre- and post-stress electrical test was performed at room and hot temperatures.

⁴ Pre- and post-stress electrical test was performed at hot, room and cold temperatures.